SHORT COMMUNICATIONS


Ba$_6$CoNb$_9$O$_{30}$ and Ba$_6$FeNb$_9$O$_{30}$: two new tungsten-bronze-type ferroelectrics. Centrosymmetry of Ba$_{3.2}$K$_{0.8}$U$_{2.4}$Nb$_{7.6}$O$_{30}$ at 300 K. Erratum

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Abstract

A printer’s error in the paper by Foster, Brown, Nielson & Abrahams [J. Appl. Cryst. (1997). 30, 495–501] is corrected. In §4.2 on p. 497, the displacement $\Delta z$(Fe1/Nb1) was given incorrectly as $0.5353 - 0.5063 = 0.1 (7)$ Å. The correct value for the displacement $\Delta z$(Fe1/Nb1) is $0.5353 - 0.5063 = 0.12 (7)$ Å.


Two-dimensional small-angle X-ray scattering investigation of stretched borosilicate glasses. Erratum

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Abstract

Printer’s errors in the paper by Polizzi, Riello, Fagherazzi, Bark & Borrelli [J. Appl. Cryst. (1997). 30, 487–494] are corrected. In the Abstract, the value of the average of the volumetric particle distribution was given incorrectly as $22 \times 70$ nm. The correct value is $22 \times 370$ nm. In §5.1 on p. 491, the size of the particles whose dimensions are very close to the volumetric average obtained by the fitting method was given incorrectly as $22 \times 80$ nm. The correct value is $22 \times 380$ nm. In §5.2 on p. 491, the unit-cell edge of Ag determined was given incorrectly as 4.709 (6) Å. The correct value is 4.079 (6) Å. The TEM micrographs of Figs. 2 and 6 were transposed. These figures are printed correctly below.

Fig. 2. TEM micrograph of sample I.

Fig. 6. TEM micrograph of sample II.